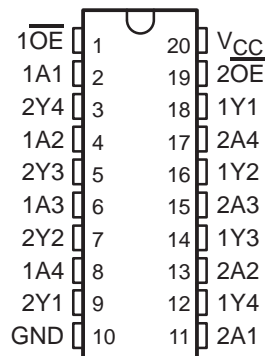


CD74FCT244, CD74FCT244AT BiCMOS OCTAL BUFFERS/LINE DRIVERS WITH 3-STATE OUTPUTS

SCBS722A – JULY 2000 – REVISED JULY 2000

- BiCMOS Technology With Low Quiescent Power
- Buffered Inputs
- Noninverted Outputs
- Input/Output Isolation From V_{CC}
- Controlled Output Edge Rates
- 64-mA Output Sink Current
- Output Voltage Swing Limited to 3.7 V
- SCR Latch-Up-Resistant BiCMOS Process and Circuit Design
- Package Options Include Plastic Small-Outline (M) and Shrink Small-Outline (SM) Packages and Standard Plastic (E) DIP

CD74FCT244, CD74FCT244AT . . . E, M, OR SM PACKAGE
(TOP VIEW)



description

The CD74FCT244 and CD74FCT244AT are octal buffer/line drivers with 3-state outputs using a small-geometry BiCMOS technology. The output stages are a combination of bipolar and CMOS transistors that limit the output high level to two diode drops below V_{CC} . This resultant lowering of output swing (0 V to 3.7 V) reduces the power-bus ringing [a source of electromagnetic interference (EMI)] and minimizes V_{CC} bounce and ground bounce and their effects during simultaneous output switching. The output configuration also enhances switching speed and is capable of sinking 64 mA.

These devices are organized as two 4-bit buffers/line drivers with separate active-low output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The CD74FCT244 and CD74FCT244AT devices are characterized for operation from 0°C to 70°C.

FUNCTION TABLE
(each buffer/driver)

INPUTS		OUTPUT
\overline{OE}	A	Y
L	H	H
L	L	L
H	X	Z



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

 **TEXAS
INSTRUMENTS**

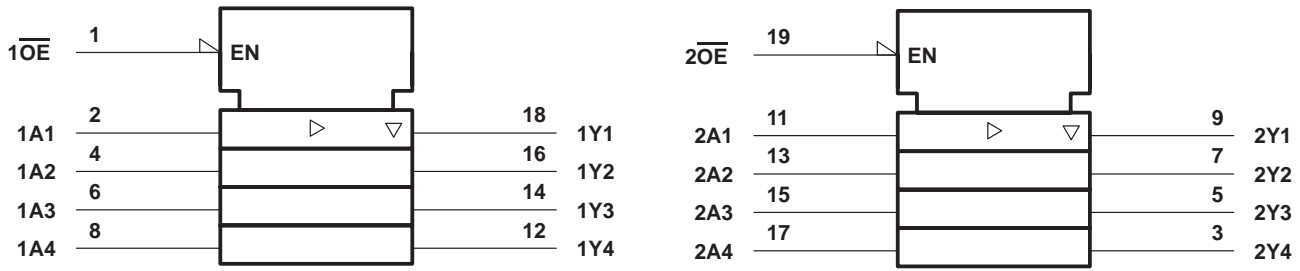
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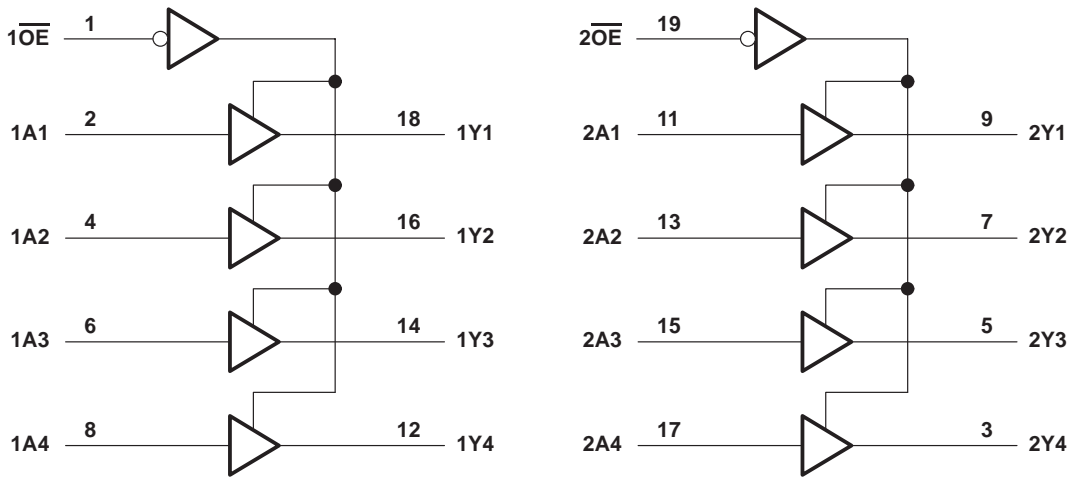
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

DC supply voltage range, V_{CC}	-0.5 V to 6 V
DC input clamp current, I_{IK} ($V_I < -0.5$ V)	-20 mA
DC output clamp current, I_{OK} ($V_O < -0.5$ V)	-50 mA
DC output sink current per output pin, I_{OL}	70 mA
DC output source current per output pin, I_{OH}	-30 mA
Continuous current through V_{CC} , I_{CC}	140 mA
Continuous current through GND	528 mA
Package thermal impedance, θ_{JA} (see Note 1): E package	69°C/W
M package	58°C/W
SM package	70°C/W
Storage temperature range, T_{stg}	-65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51.



CD74FCT244, CD74FCT244AT

BiCMOS OCTAL BUFFERS/LINE DRIVERS WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 2)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	4.75	5.25	V
V _{IH}	High-level input voltage	2		V
V _{IL}	Low-level input voltage		0.8	V
V _I	Input voltage	0	V _{CC}	V
V _O	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current		-15	mA
I _{OL}	Low-level output current		64	mA
Δt/Δv	Input transition rise or fall rate (slew rate)	0	10	ns/V
T _A	Operating free-air temperature	0	70	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C		MIN	MAX	UNIT
			MIN	MAX			
V _{IK}	I _I = -18 mA	4.75 V		-1.2		-1.2	V
V _{OH}	I _{OH} = -15 mA	4.75 V	2.4		2.4		V
V _{OL}	I _{OL} = 64 mA	4.75 V	0.55		0.55		V
I _I	V _I = V _{CC} or GND	5.25 V		±0.1		±1	μA
I _{OZ}	V _O = V _{CC} or GND	5.25 V		±0.5		±10	μA
I _{OS} [†]	V _I = V _{CC} or GND, V _O = 0	5.25 V		-60		-60	mA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	5.25 V		8		80	μA
ΔI _{CC} [‡]	One input at 3.4 V, Other inputs at V _{CC} or GND	5.25 V		1.6		1.6	mA
C _i	V _I = V _{CC} or GND			10		10	pF
C _o	V _O = V _{CC} or GND			15		15	pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 100 ms.

[‡] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.25 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	CD74FCT244			CD74FCT244AT			UNIT
			T _A = 25°C		T _A = 25°C				
			TYP	MIN	MAX	TYP	MIN	MAX	
t _{pd}	A	Y	4.5	1.5	6.5	3.8	1.5	5.3	ns
t _{en}	$\overline{\text{OE}}$	Y	6	1.5	8	4.8	1.5	6.5	ns
t _{dis}	$\overline{\text{OE}}$	Y	5	1.5	7	4.5	1.5	5.8	ns

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C

PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)} Quiet output, maximum dynamic V _{OL}		1		V
V _{OH(V)} Quiet output, minimum dynamic V _{OH}		0.5		V
V _{IH(D)} High-level dynamic input voltage	2			V
V _{IL(D)} Low-level dynamic input voltage			0.8	V



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WITH 3-STATE OUTPUTS

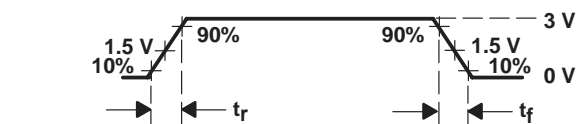
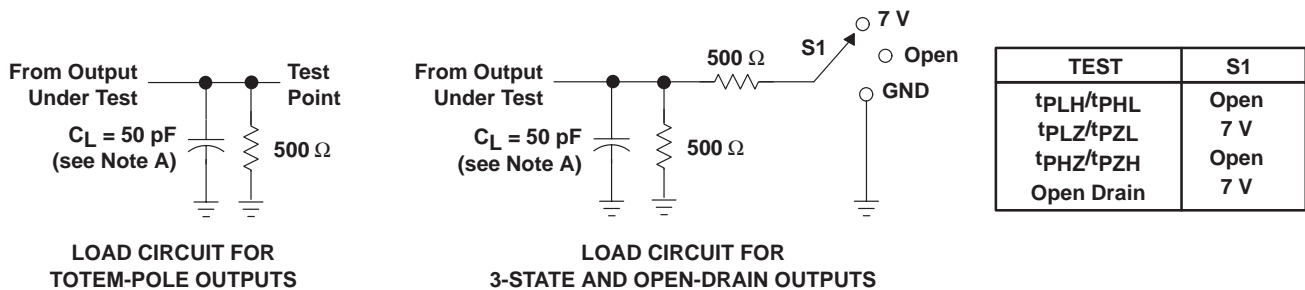
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operating characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

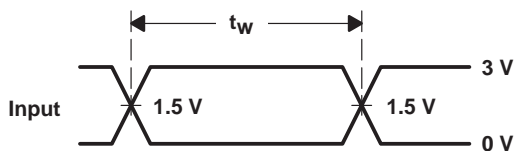
PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	No load, $f = 1\text{ MHz}$	35	pF



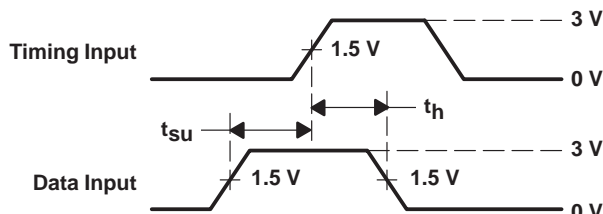
PARAMETER MEASUREMENT INFORMATION



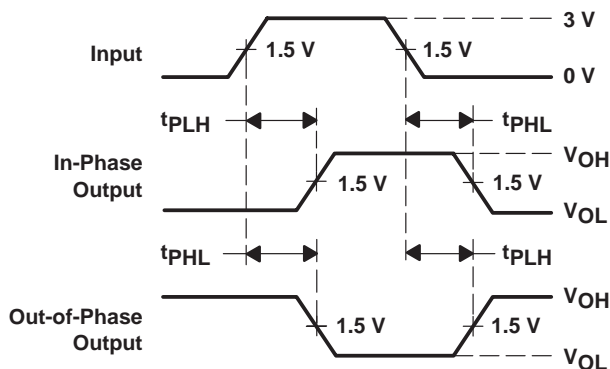
VOLTAGE WAVEFORM
INPUT RISE AND FALL TIMES



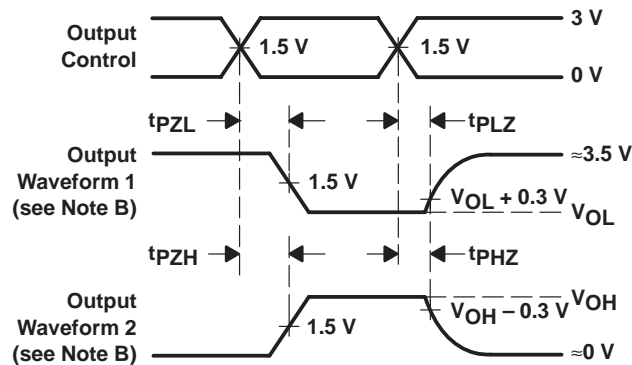
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r and t_f = 2.5 ns.
D. The outputs are measured one at a time with one input transition per measurement.
E. t_{PZL} and t_{PZH} are the same as t_{dis}.
F. t_{PZL} and t_{PZH} are the same as t_{en}.
G. t_{PHL} and t_{PLH} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

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